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TITLE: TRANSMISSION TEST CIRCUIT
FOR INPUT AND OUTPUT DEVICE

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INVENTOR-INFORMATION:
NAME

NISHIJIMA, TADASHI

ASSIGNEE-INFORMATION:
NAME

COUNTRY

TOSHIBA CORP

N/A

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ABSTRACT:

PURPOSE: To check the operation of a
transmission system, by receiving a
signal transmitted from a data processor at an

input and output device and transmitting data as they are, receiving the data at the processor again and processing of coincidence of comparison.

CONSTITUTION: When a transmission test circuit selecting switch 32 of an input and output device selects a position 34, an address of an IC memory 26 consists of a reception area from a data processor and a transmission area 37 to the data processor. When the switch 32 selects a position 33, the address most significant digit of the IC memory 26 is fixed to logical 1, then the reception area from the data processor is the same area as the transmission area 37. Thus, the data received from the data processor is a transmission signal to the data processor as it is, and the comparison between transmission and reception data at the data processor allows the overall transmission test for the transmission system consisting of the data processor, a transmission line and the input and output device.

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